Search Notes

Application/Control No. 10/767,725	Applicant(s)/Patent unde Reexamination
	OGAWA, HIDEHIKO
Examiner	Art Unit
Thomas D. Lee	2625

SEARCHED				
Class	Subclass	Date	Examiner	
358	1.15, 402, 440	12/8/2005	TDL	
379	100.01	12/8/2005	TDL	
379	100.08	12/8/2005	TDL	
379	100.13	12/8/2005	TDL	
379	100.17	12/8/2005	TDL	
updated		5/23/2006	TDL	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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